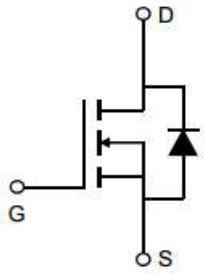
迈诺斯科技

MDT20P04D

Silicon P-Channel Power MOSFET

Description

The MDT20P04D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge. It can be used in a wide variety of applications.



TO-252

KEY CHARACTERISTICS

① V_{DS} = -40V,I_D =-20A
② $R_{DS(ON)}$ < 35mΩ @ V_{GS}=-10V $R_{DS(ON)}$ < 45mΩ @ V_{GS}=-4.5V
③ High density cell design for lower Rdson
④ Fully characterized avalanche voltage and current
⑤ Good stability and uniformity with high E_{AS}
⑥ Excellent package for good heat dissipation

Application

① Power switching application
② Hard switched and High frequency circuits
Uninterruptible power supply

ORDERING INFORMATION

Ordering Codes	Package	Product Code	Packing
MDT20P04D	TO-252	MDT20P04D	Reel

Absolute Maximum Ratings (TA=25℃ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	-40	V
Gate-Source Voltage	V_{GS}	±20	V
Drain Current-Continuous	I_D	-20	A
Drain Current-Pulsed (Note 1)	I_{DM}	-60	A
Maximum Power Dissipation(Tc=25℃)	P_D	50	W
Operating Junction and Storage Temperature Range	T_J,T_{STG}	-55 To 175	℃

Thermal Characteristic

Thermal Resistance,Junction-to-Ambient (TO-252)	$R_{\theta JC}$	3.0	℃/W
Thermal Resistance,Junction-to-Ambient (SOP-8)	$R_{\theta JA}$	57	℃/W

Electrical Characteristics (TA=25℃ unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	V_{GS}=0V I_D=-250μA	-40	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS}=-40V,V_{GS}=0V	-	-	-1	μA
Gate-Body Leakage Current	I_{GSS}	V_{GS}=±20V,V_{DS}=0V	-	-	±100	nA
On Characteristics						
Gate Threshold Voltage	$V_{GS(th)}$	V_{DS}=V_{GS},I_D=-250μA	-1.0	-1.5	-2.4	V
Drain-Source On-State Resistance(Note 2)	$R_{DS(ON)}$	V_{GS}=-10V, I_D=-10A	-	29	35	mΩ
		V_{GS}=-4.5V, I_D=-5A	-	34	45	
Forward Transconductance	g_{FS}	V_{DS}=-5V,I_D=-15A	-	10	-	S
Dynamic Characteristics (Note 3)						
Input Capacitance	C_{lss}	V_{DS}=-20V,V_{GS}=0V, f=1.0MHz	-	930	-	pF
Output Capacitance	C_{oss}		-	85	-	pF
Reverse Transfer Capacitance	C_{rss}		-	35	-	pF
Switching Characteristics (Note 3)						
Turn-on Delay Time	$t_{d(on)}$	V_{DD}=-20V, R_L=-1Ω, V_{GS}=-10V,R_{GEN}=3Ω	-	8	-	ns
Turn-on Rise Time	t_r		-	4	-	ns
Turn-Off Delay Time	$t_{d(off)}$		-	32	-	ns
Turn-Off Fall Time	t_f			7	-	ns
Total Gate Charge	Q_g	V_{DS}=-20V,I_D=-15A V_{GS}=-10V	-	25	-	nC
Gate-Source Charge	Q_{gs}		-	3	-	nC
Gate-Drain Charge	Q_{gd}		-	7	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage	V_{SD}	V_{GS}=0V,I_S=-15A	-	-	-1.2	V

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
3. Guaranteed by design, not subject to production.

Characteristics Curves

Figure 1 Output Characteristics	Figure 2 Transfer Characteristics

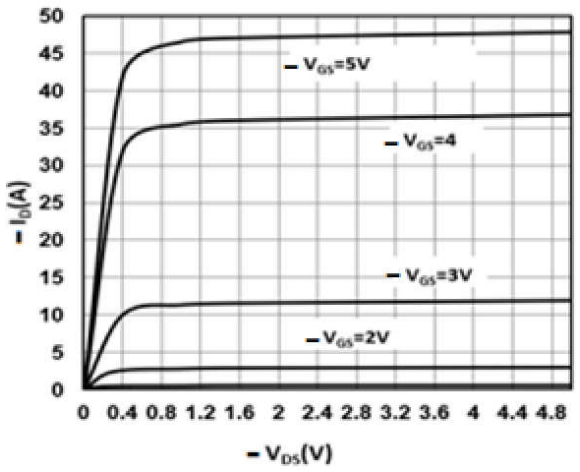
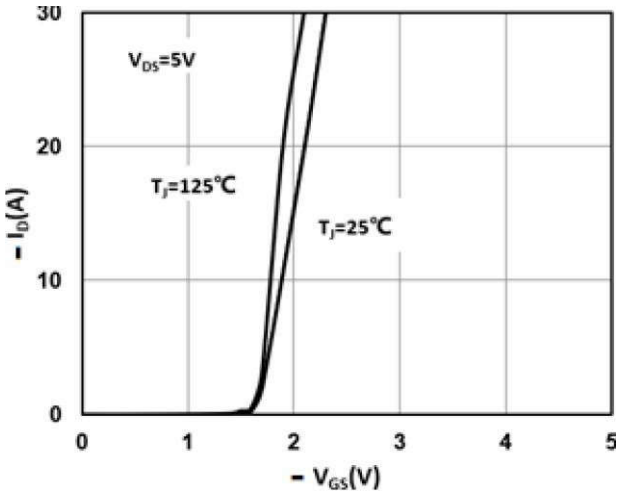

	

Figure 3 On-Resistance vs. I_D and V_{GS}	**Figure 4 On-Resistance vs. Junction Temperature**

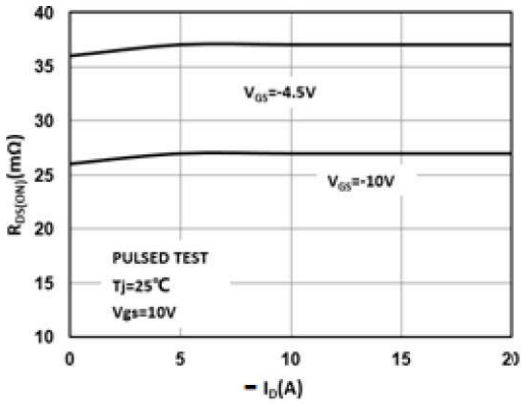
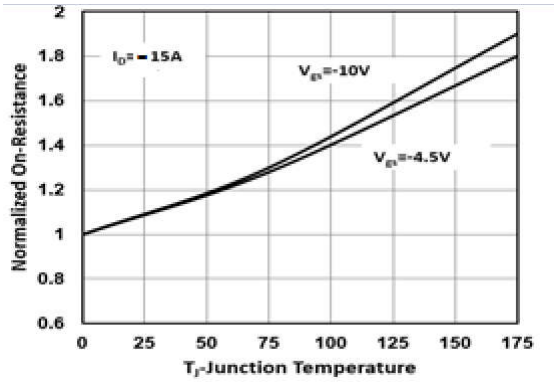

	

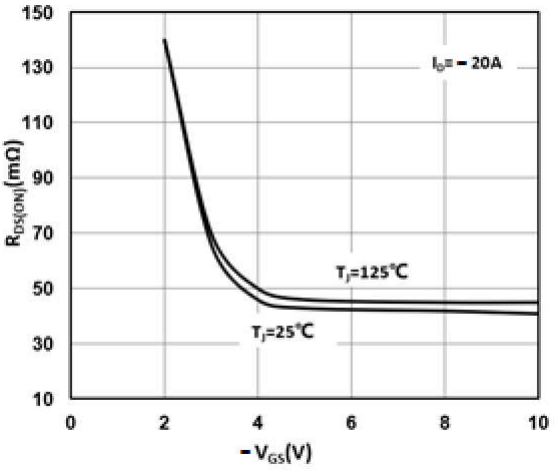
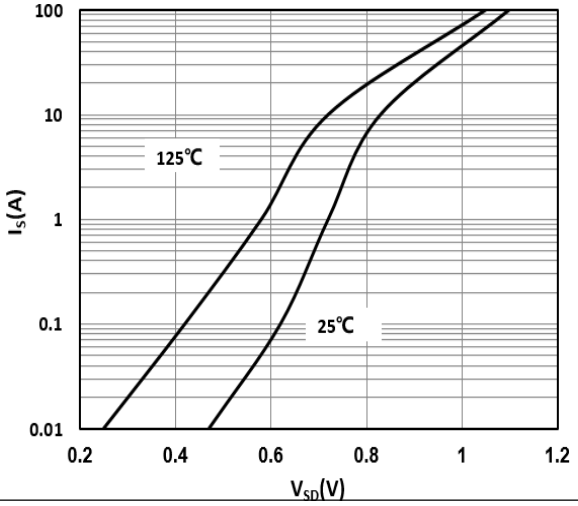
Figure 5 On-Resistance vs. V_{GS}	**Figure 6 Body Diode Forward Voltage**
	

Figure 7 Gate-Charge Characteristics

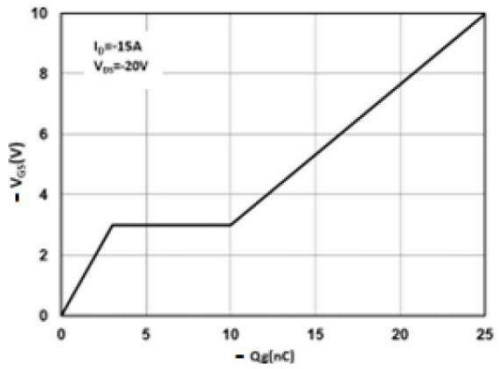


Figure 8 Capacitance Characteristics

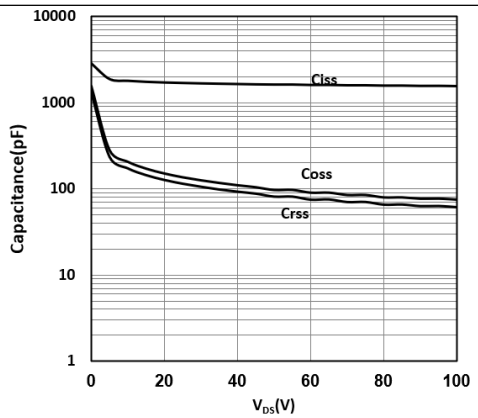


Figure 9 Maximum Forward Biased Safe Operation Area(TO-252)

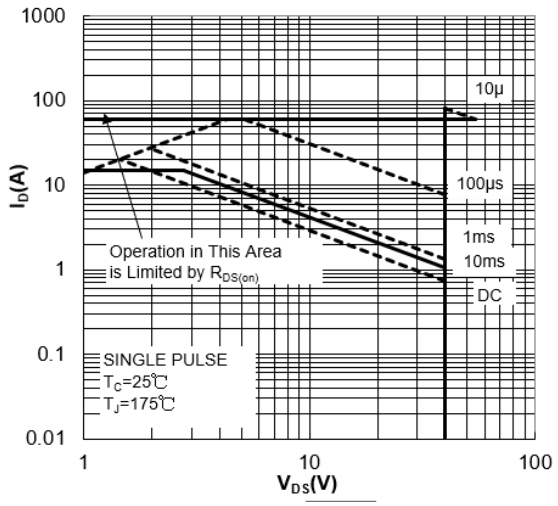


Figure 10 Single Pulse Power Rating Junction-to-Ambient(TO-252)

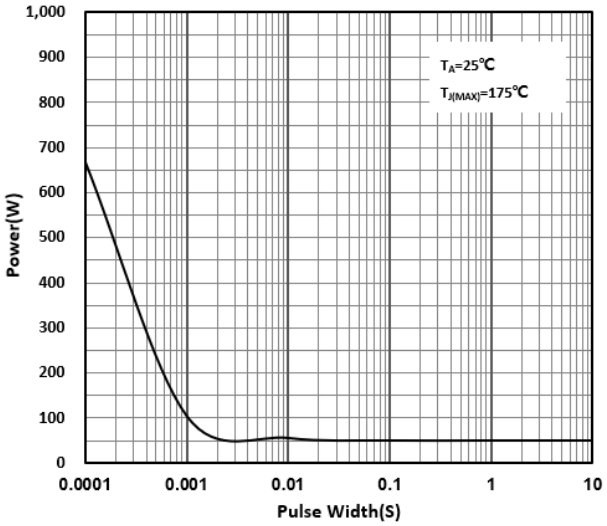


Figure 11 Normalized Maximum Transient Thermal Impedance(TO-252)

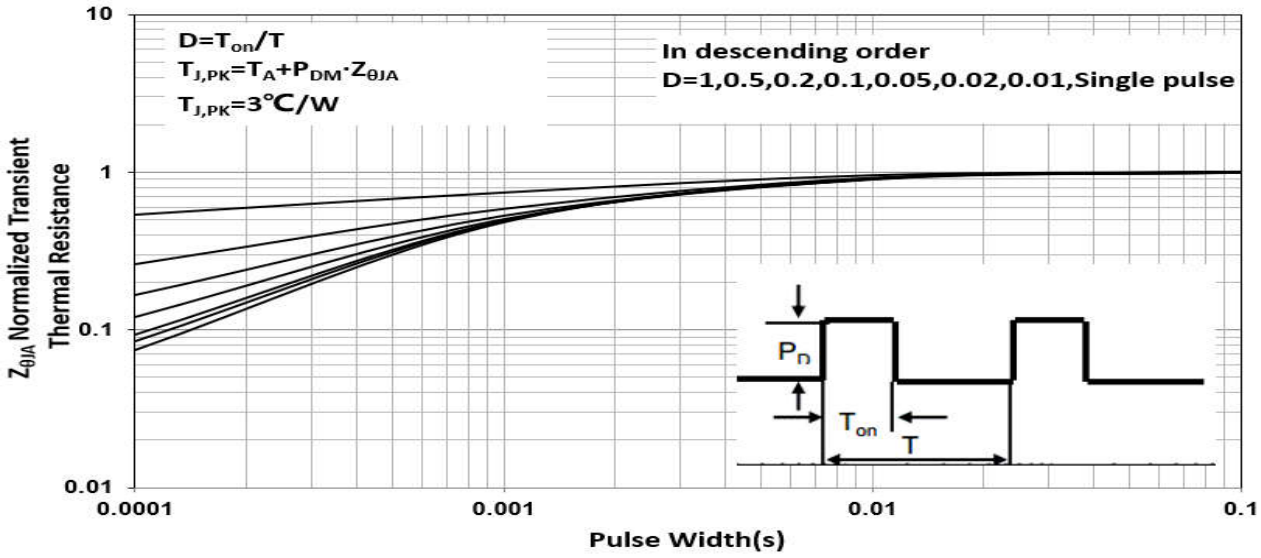


Figure 9 Maximum Forward Biased Safe Operation Area(SOP-8)

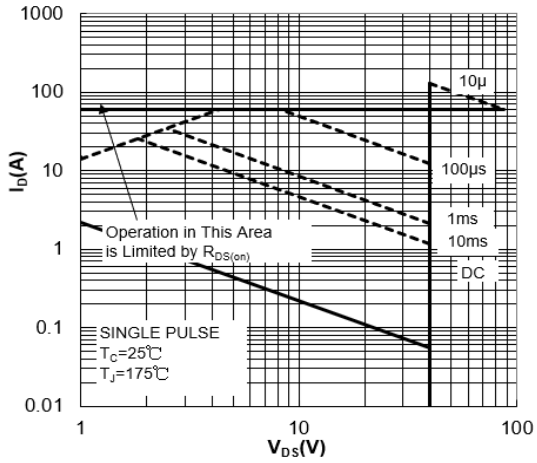


Figure 10 Single Pulse Power Rating Junction-to-Ambient(SOP-8)

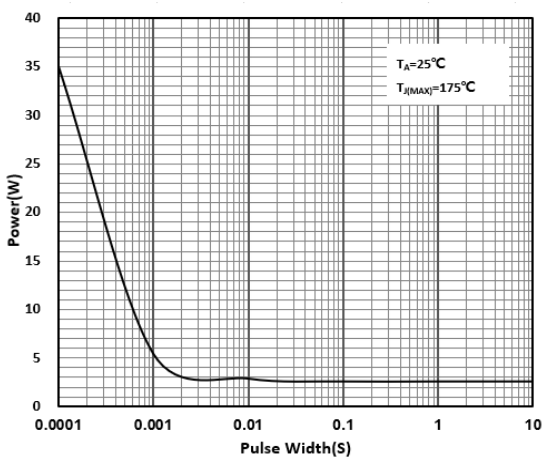
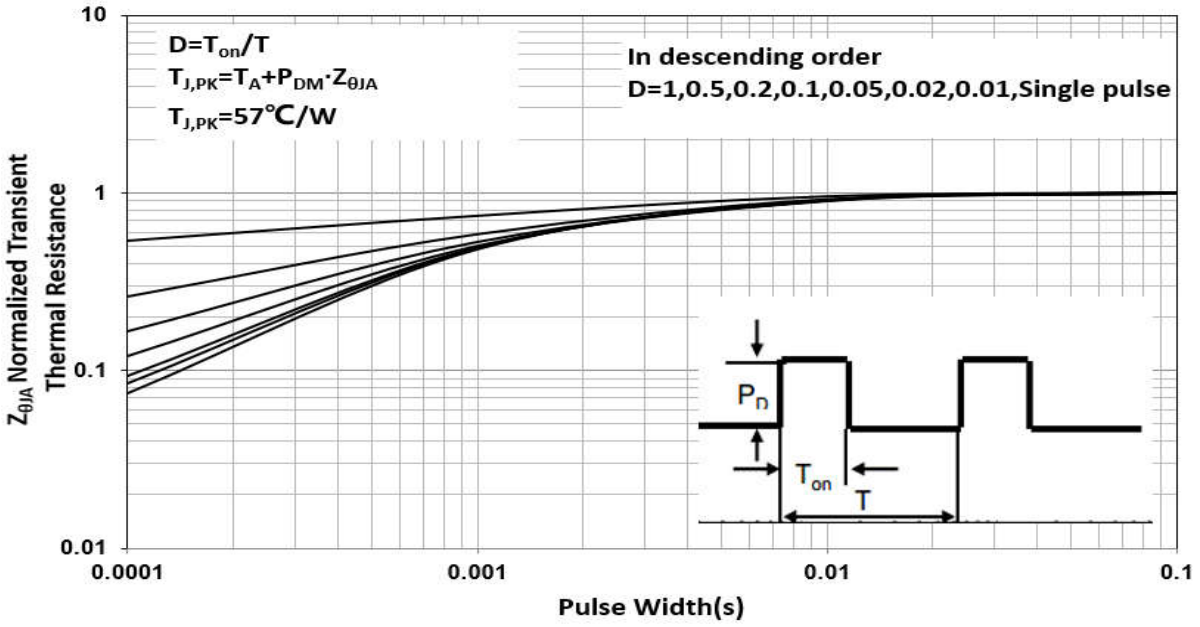
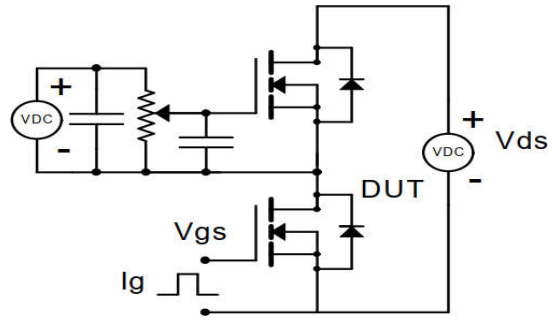
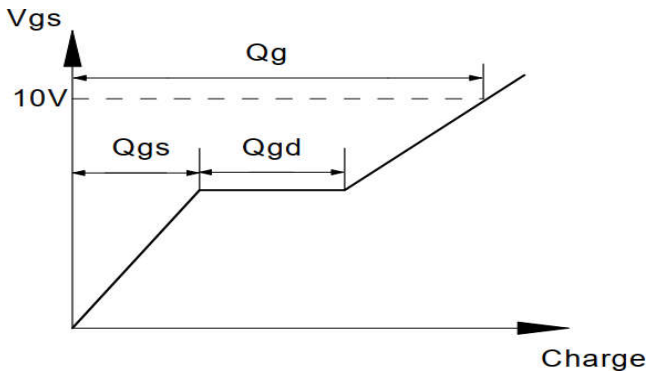
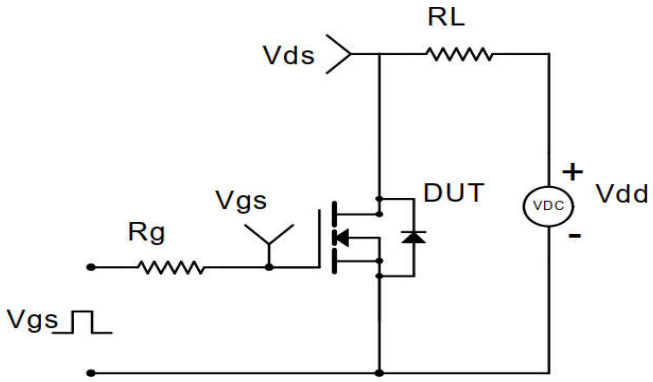
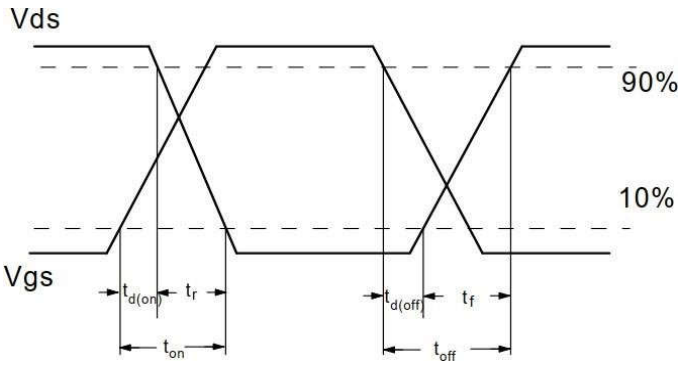
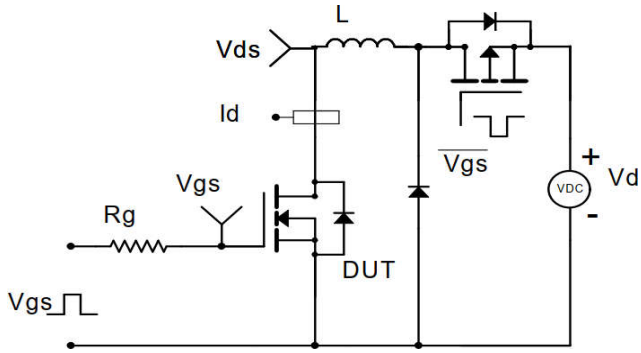
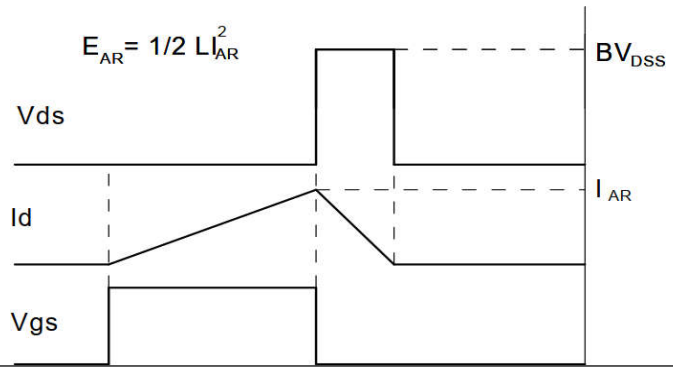
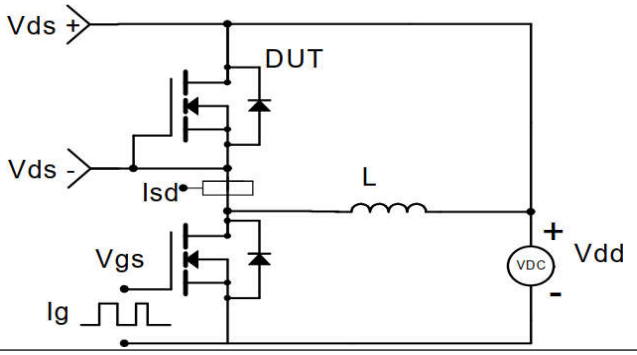
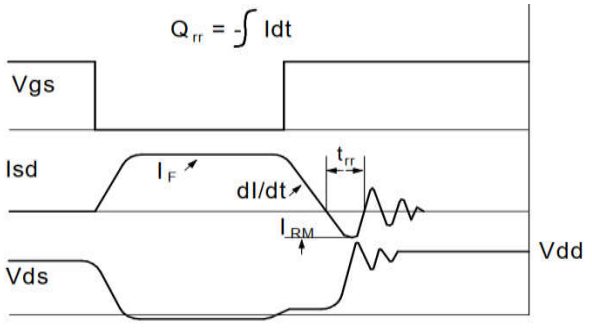


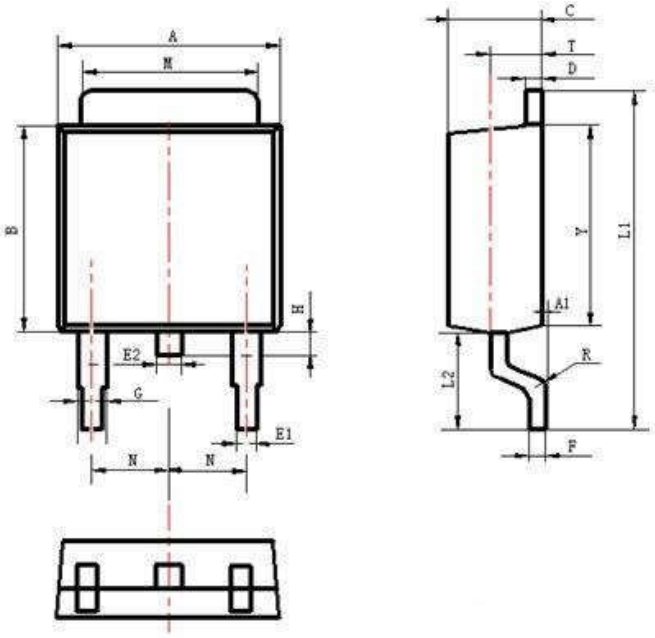
Figure 11 Normalized Maximum Transient Thermal Impedance(SOP-8)



Test Circuit and Waveform

Gate Charge Test Circuit	Gate Charge Test Waveform
	
Resistive Switching Test Circuit	**Resistive Switching Test Waveforms**
	
Unclamped Inductive Switching (UIS) Test Circuit	**Unclamped Inductive Switching (UIS) Test Waveforms**
	
Diode Recovery Test Circuit	**Diode Recovery Test Waveforms**
	

Package Description



Items	Values(mm)	
	MIN	MAX
A	6.30	6.90
A1	0	0.13
B	5.70	6.30
C	2.10	2.50
D	0.30	0.60
E1	0.60	0.90
E2	0.70	1.00
F	0.30	0.60
G	0.70	1.20
L1	9.60	10.50
L2	2.70	3.10
H	0.60	1.00
M	5.10	5.50
N	2.09	2.49
R	0 .3	
T	1.40	1.60
Y	5.10	6.30

TO-252 Package

NOTE:

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shenzhen Minos reserves the right to make changes in this specification sheet and is subject to change withoutprior notice.

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